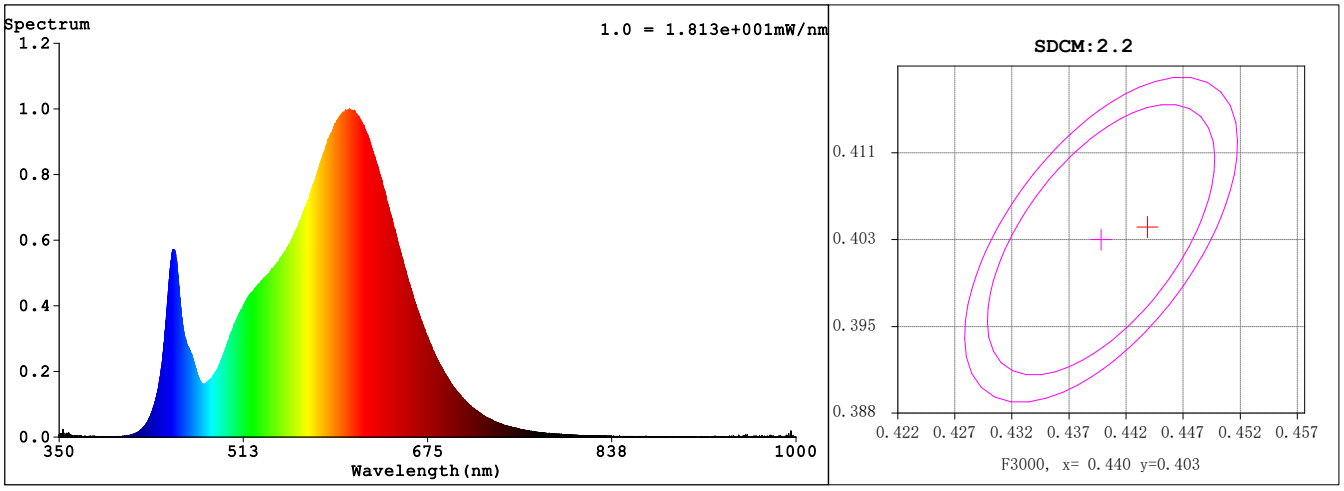
Spectrum Test Report

Sample	:	Date	: 2025-05-27 08:37:01
Specification	: 48200801 3000K	Sam. Status	:
Sample No.	: 1	Instrument	: HAAS-2000(EVERFINE)
Manufacturer	: M-ELEC	Test by	: DAMIN
		Assessor	: CHEN SONG YU

Test Condition

Temperature	: 25.3Deg	RH	: 65.0%
WL Range	: 350nm-1000nm	IP	: 52100 (80%)
Test Mode	: Fast Test	T	: 3225 ms
		Sensitivity	: Low

Spectrum



Colorimetric Parameters

Chromaticity Coordinate: x = 0.4441 y = 0.4041 / u' = 0.2552 v' = 0.5225 (duv=-1.61e-03)

CCT= 2883K Prcp WL: Ld=583.6nm Purity=54.6%

Peak WL: Lp=606nm FWHM: =121.1nm Ratio:R=23.8% G=73.7% B=2.5%

Render Index: Ra = 83.4

R1 =83	R2 =92	R3 =96	R4 =82	R5 =83	R6 =91	R7 =82	
R8 =59	R9 =9	R10=82	R11=82	R12=74	R13=85	R14=99	R15=75

LEVEL:OUT

Photometric & Radiometric Parameters

Flux = 788.39 lm Eff. : 103.76 lm/W Fe = 2.6093 W

Electrical parameters

V = 230.2 V I = 0.03473 A P = 7.598 W PF = 0.9506

Kdisp(IEC) = 0.9646 Freq=49.99 Hz

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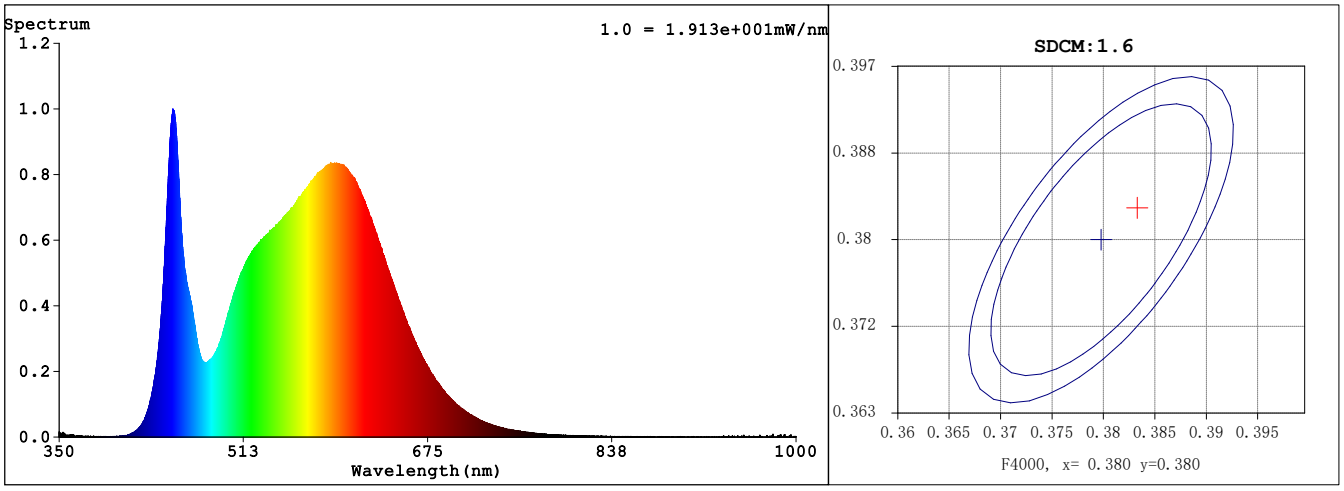
Spectrum Test Report

Sample	:	Date	: 2025-05-27 08:38:48
Specification	: 48200801 4000K	Sam. Status	:
Sample No.	: 2	Instrument	: HAAS-2000(EVERFINE)
Manufacturer	: M-ELEC	Test by	: DAMIN
		Assessor	: CHEN SONG YU

Test Condition

Temperature	: 25.3Deg	RH	: 65.0%
WL Range	: 350nm-1000nm	IP	: 52113 (80%)
Test Mode	: Fast Test	T	: 3467 ms
		Sensitivity	: Low

Spectrum



Colorimetric Parameters

Chromaticity Coordinate: x = 0.3835 y = 0.3831 / u' = 0.2246 v' = 0.5048 (duv=1.64e-03)

CCT= 3965K Prcp WL: Ld=578.2nm Purity=30.1%

Peak WL: Lp=450nm FWHM: =19.1nm Ratio:R=18.1% G=78.5% B=3.5%

Render Index: Ra = 82.1

R1 =80	R2 =88	R3 =94	R4 =81	R5 =80	R6 =84	R7 =86	
R8 =63	R9 =4	R10=72	R11=80	R12=59	R13=82	R14=97	R15=74

LEVEL:OUT

Photometric & Radiometric Parameters

Flux = 854.00 lm Eff. : 110.93 lm/W Fe = 2.7720 W

Electrical parameters

V = 230.1 V I = 0.03515 A P = 7.698 W PF = 0.9517

Kdisp(IEC) = 0.9655 Freq=49.99 Hz

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